

FORM PTO-1449
U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

NOV 24 2003

PATENT & TRADEMARK OFFICE

DOCKET NO: 006726 USA/ETCH/CONE/JB

APPLICATION NO.:
10/646,943INFORMATION DISCLOSURE STATEMENT
IN AN APPLICATION

APPLICANT: Barnes et al.

FILING DATE: 8/21/2003

GROUP ART UNIT:
Unknown

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
SN	4	6	1	1	9	1	9	09/16/1986	Brooks, Jr. et al.			
	4	8	4	2	6	8	3	06/27/1989	Cheng et al.			
	4	8	6	7	8	4	1	09/19/1989	Loewenstein et al.			
	4	9	2	4	8	0	7	05/15/1990	Nakayama et al.			
	4	9	3	1	1	3	5	06/05/1990	Horiuchi et al.			
	4	9	3	5	6	6	1	06/19/1990	Heinecke et al.			
	4	9	5	3	9	8	2	09/04/1990	Ebbing et al.			
	4	9	6	0	4	8	8	10/02/1990	Law et al.			
	4	9	8	0	2	0	4	12/25/1990	Fuji et al.			
SN	5	0	7	0	8	1	4	12/10/1991	Whiffin et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
												YES NO	
SN	3	2	8	1	7	8	0	12/12/1991	Japan				Abstract
↑	6	1	3	2	2	2	3	05/13/1994	Japan				Abstract
	5	0	4	7	7	0	7	02/26/1993	Japan				Abstract
	6	1	2	4	1	9	30	10/28/1986	Japan				Abstract
	3	2	8	1	7	8	0	12/12/1991	Japan				Abstract
	1	2	4	8	5	2	0	10/04/1989	Japan				Abstract
	1	8	9	9	2	8		09/27/1985	Japan				Abstract
	6	1	2	4	9	0	9	05/06/1994	Japan				Abstract
	0	8	1	0	6	3	0	12/03/1997	EP				X
↓	0	7	2	1	2	1		04/02/1987	Japan				X
SN	9	6	1	9	8	2	5	06/27/1996	PCT				x

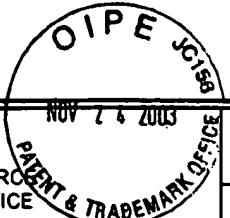
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

SN	Zhang et al., "Automated Process Control of Within-Wafer and Wafer-to-Wafer Uniformity in Oxide CMP", CMP-MIC, March 2002
GN	NANOMETRICS Applications Note, "Optical Measurement of Critical Dimensions", August 2001

EXAMINER	<i>Brodwin</i>	DATE CONSIDERED	<i>17/19/04</i>
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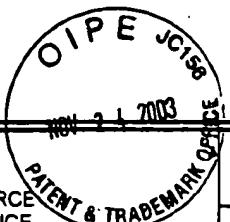
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		NOV 26 2003	DOCKET NO: 006726 USA/ETCH/CONE/JB		APPLICATION NO.: 10/646,943								
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		FILING DATE: 8/21/2003				GROUP ART UNIT: Unknown							
U.S. PATENT DOCUMENTS													
EXAMINER INITIAL	DOCUMENT NUMBER						DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE		
<i>SN</i>	5	0	8	4	1	2	6	01/28/1992	McKee	—	—		
	5	2	4	4	5	0	1	09/14/1993	Nakayama et al.				
	5	2	5	2	1	7	8	10/12/1993	Moslehi				
	5	2	6	9	8	4	7	12/14/1993	Anderson et al.				
	5	3	7	2	6	7	3	12/13/1994	Slager et al.				
	5	3	8	9	1	9	7	02/14/1995	Ishimaru				
	5	4	0	5	4	8	8	04/11/1995	Dimitrelis et al.				
	5	4	2	7	8	7	8	06/27/1995	Corliss				
	5	4	5	3	1	2	4	09/26/1995	Moslehi et al.				
<i>SW</i>	5	5	2	2	9	3	4	06/04/1996	Suzuki et al.	—	—		
FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
												YES	NO
<i>SN</i>	0	7	0	2	3	9	2	03/20/1996	EP			X	
	9	9	5	7	7	4	7	11/11/1999	PCT			X	
	0	4	1	0	4	4	2	07/26/1990	EP			X	
<i>SN</i>	9	8	0	0	5	7	6	01/08/1998	PCT			X	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)													
EXAMINER	<i>Sandy M</i>											DATE CONSIDERED	<i>7/19/04</i>
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EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE	
<i>SN</i>	6	3	0	3	5	0	7	10/16/2001	Wang et al.				
	6	3	3	3	2	7	2	12/25/2001	McMillan et al.				
	6	3	5	0	3	9	0	02/26/2002	Liu et al.				
	6	3	8	8	2	5	3	05/14/2002	Su				
	6	4	0	3	4	9	1	06/11/2002	Liu et al.				
	0	1	8	8	4	1	7	12/12/2002	Levy et al.				
<i>SN</i>	0	0	1	1	7	8	6	01/16/2003	Levy et al.				
FOREIGN PATENT DOCUMENTS										TRANSLATION			
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB-CLASS	YES	NO
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EXAMINER	<i>Sanghyun</i>									DATE CONSIDERED <i>7/19/04</i>			
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